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SHEET 1 OF 1

LIST OF ART CITED BY APPLICANT (PTO-1449)				ATTY. DOCKET NO. P-0641		APPLN. SERIAL NO. 10/775,210	
				APPLICANT(S) In-Kyoung KIM			
				FILING DATE February 11, 2004		GROUP 2681	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
/BD/	6,351,499 B1	02/26/2002	PAULRAJ et al.				
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	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No	
/BD/	CN 1656726	08/17/2005	China (English Abstract and Chinese Full Text)			X	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
/BD/	Office Action dated November 25, 2005 in Chinese Application No. 200410005504.9						
EXAMINER				DATE CONSIDERED			
/Betsy Deppe/				05/14/2007			

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